

Application/Control No.	Applicant(s)/Patent under Reexamination
10/713,478	HUIK, HEIKKI
Examiner	Art Unit
Anthony Weier	1794

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	SEARCHED				
Class	Subclass	Date	Examiner		
99	323.3, 282, 283, 300, 301, 307		3		
426	433	11/15/2007	AW		
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INT	ERFERENC	ERENCE SEARCHED		
Class	Subclass .	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
•	DATE	EXMR		
Inventor Search	1,1/15/2007	AW		
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